CRYSTAL UNITS

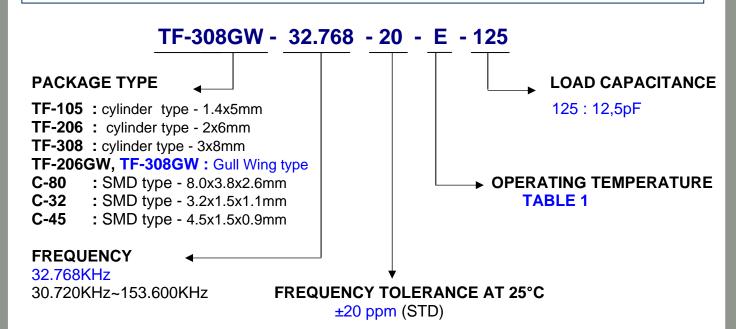






- Photolithography finished allows uniform stable performance
- Excellent shock resistance and environmental capability
- Low power consumption
- Suitable for time-keeping of clock and microcomputer

PART NUMBER GUIDE



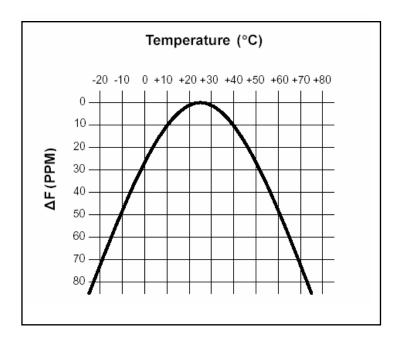
ELECTRICAL SPECIFICATIONS

MODEL	TF serie
Nominal Frequency	32.768KHz
Operating Temperature Range	-20 to +70°C(STD)
Storage Temperature Range	-55 to +125°C
Frequency Tolerance (at 25°C)	+/-20ppm
Temperature Coefficient (frequency)	-0.034ppm/ °C² Max
Load Capacitance (CL)	12.5pF
Drive Level	1.0 μWMax
Series Resistance	40kΩ Max
Shunt Capacitance (Co)	1.0pF
Aging (at 25°C)	3.0ppm/year Max

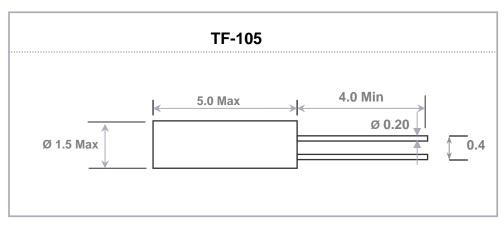
TABLE 1

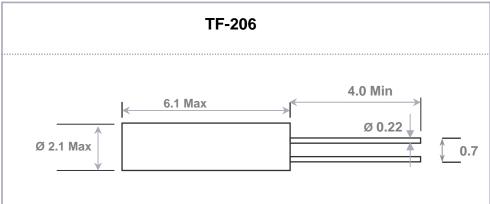
OPERATING TEMPERATURE RANGE			
-10~+60°C	Α		
-20~+60°C	В		
0~+70°C	С		
-10~+70°C	D		
-20~+70°C	E		
-30~+60°C	F		
-20~+85°C	G		
-30~+70°C	Н		
-30~+85°C	I		
-40~+85°C	J		

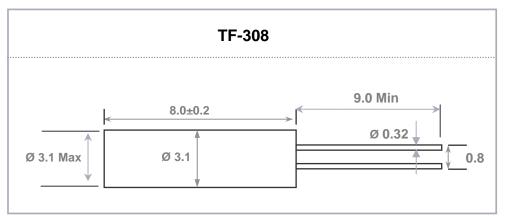
TEMPERATURE CHARACTERISTIC

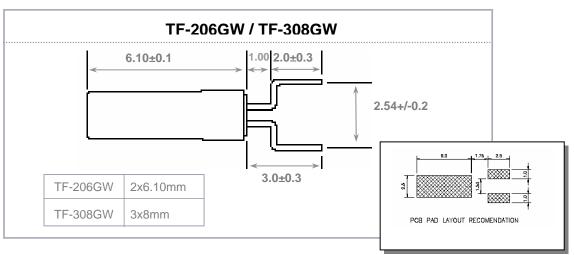


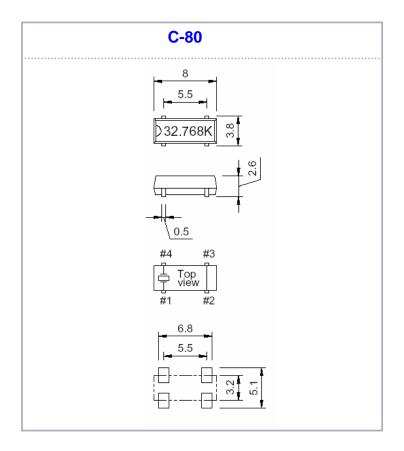
MECHANICAL DIMENSION

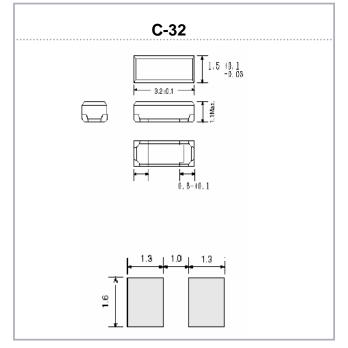


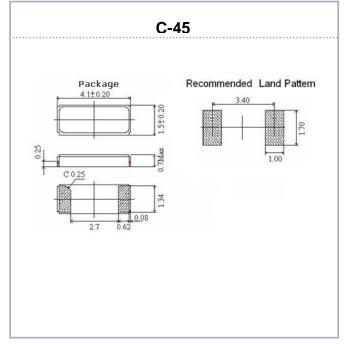




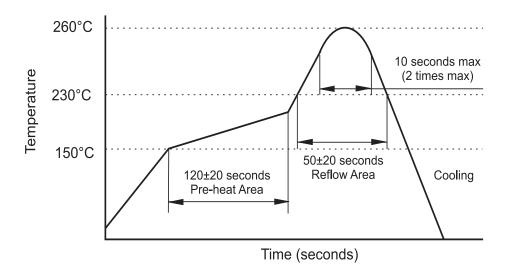








SOLDERING REFLOW





Pb-free compliance

Component and Assembly Pb content shall be less than 0.1% by weight of the device (in accordance with IPC/EIA J-STD-006) and shall not be intentionally introduced.

Product Information

For a product to be RoHS compliant, it must satisfy several conditions:

- Contain no more than the specified limits of the target hazardous substances set out in the RoHS Directive
- Able to withstand Pb-free 260°C solder reflow profile below
- External packaging and terminations are Pb-free
- Internal PCB, components, solders, and terminations are Pb-free

SPECIFICATION OF CRYSTAL

Reliability Test (applicable to OSC and SMD type X'tal)

Test Items	Test Condition	Specification	
Test Items	Test Items Test Condition		General X' tal (Note:2)
Gross Leak Test	FC-40 125°C/30sec	No continuous bubble	
2. Fine Leak Test	Bombing of He 5kg/cm ² for 2 hours	Less than 1*10^-8atm.c.c./sec, Helium	
3. Drop Test	Free dropped a ~19.999MHz(Fund.) →100 cm height b. 20~29.999MHz(Fund.) →50 cm height c. 30~ MHz(Fund.) →20 cm height	△F≦± 10PPM, Duty within spec.	△F≦±10PPM, △C.I.≦±10ohms
4. Vibration Test	on a hard wooden board for 3 times (board is thickness more than 30 mm) Freq. range: 10~55Hz	△F≦±10PPM,	△F≦±10PPM,
	Peak to peak amplitude:1.5mm Peak acceleration:10 G 3 direction(X,Y,Z), each 60min.	Duty within spec.	△C.I.≦±10ohms
Soldering Test times.Peak b. Dip termin	a. IR Reflow furnace with the condition 2 times.Peak temp.260±3°C , 10sec(Min.)	△F≦±10PPM, Duty within spec. For SMD OSC only	△F≦±10PPM, △C.I.≦±10ohms
	b. Dip terminals in a 260±5°C solder bath for 5±0.5 sec.	At least 90% of each dipped area shall be covered by fresh solder. For DIP OSC only.	NA
6. Bending Test	Bending cycle: 1 cycle 0°->45°->0°->45°->0°	△F≦±5PPM, Duty within spec. For DIP OSC only.	NA
7. Share Test	Weight: 10N, Test duration: 10±1 sec	△F≦±5PPM, Duty within spec. For SMD OSC only.	△F≦±10PPM, △C.I.≦±10ohms
8. Low Temp. Exposure Test	-40±3℃, 240±12 hrs	$\triangle F \leq \pm 10 PPM$, Duty within spec.	△F≦±10PPM, △C.I.≦±10ohms
9. Aging Test	125±3℃, 240±12hrs	△F≦±10PPM, Duty within spec.	△F≦±10PPM, △C.I.≦±10ohms
10. High Temp. & Humidity Test	+85°C±5°C & 85%±5% R.H., 240±12 hrs	$\triangle F \leq \pm 10 PPM$, Duty within spec.	△F≦±10PPM, △C.I.≦±10ohms
11. Temperature Cycling Test	-40±3°C/15±3min ~ +85±3°C/15±3min 15cycles	△F≦±10PPM, Duty within spec.	△F≦±10PPM, △C.I.≦±10ohms

Note:1 \rightarrow For communication application the spec. demanded $\underline{\text{``} \triangle F \leq \pm 5 \text{ PPM, Duty within spec.''}}$ \circ

Note:2 \rightarrow For communication application the spec. demanded $\underline{\text{"$\triangle$F$$}$$ \leq \pm 5 PPM, \triangle C.I.$$ \leq \pm $5 ohms "}$